

Notice of References Cited

Application/Control No.

10/825,528

Applicant(s)/Patent Under
Reexamination
SHEN ET AL.

Examiner

Anthony Weier

Art Unit

1761

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,858,442	01-1999	Payne et al.	426/574
	B	US-			
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	D	US-			
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	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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